STUDIES OF THE MICRO-BUNCHING INSTABILITY IN THE PRESENCE OF A DAMPING WIGGLER

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Abstract

At the KIT storage ring KARA (KArlsruhe Research Accelerator), the momentum compaction factor can be reduced leading to natural bunch lengths in the ps range. Due to the high degree of longitudinal compression, the micro-bunching instability arises. During this longitudinal instability, the bunches emit bursts of intense coherent synchrotron radiation in the THz frequency range caused by the complex longitudinal dynamics. The temporal pattern of the emitted bursts depends on given machine parameters, like momentum compaction factor, acceleration voltage, and damping time. In this paper, the influence of the damping time is studied by utilizing the CLIC damping wiggler prototype installed in KARA as well as by simulations using the Vlasov-Fokker-Planck solver Inovesa.

INTRODUCTION

The micro-bunching instability, a longitudinal instability, occurs for short electron bunches when their own electric field acts back on their longitudinal charge distribution. At the right conditions (e.g. bunch current, bunch length, momentum compaction factor and damping time), substructures form and lead to the emission of intense coherent synchrotron radiation (CSR) at wavelengths shorter than the bunch length. This radiation acts back on the bunch profile and creates a self-enhancing effect. This interaction can be described via the CSR impedance using the parallel plates model [1]. It was shown that by solving the Vlasov-Fokker-Planck equation with the parallel plates impedance as a perturbation in the Hamiltonian, the instability threshold [2, 3] and even the behavior of the instability above the threshold current is reproduced to a great extend [4]. By observing the emitted power of the synchrotron radiation, in the frequency range corresponding to the size of the substructures (at KARA in the THz range), the temporal development of the bunch profile due to the instability can be studied. The emitted synchrotron radiation spectrum directly depends on the longitudinal charge density and changes therefore with the rising and vanishing of substructures therein. The development of the temporal emission spectrum over the decreasing bunch current (Fig. 1) is reproducible for the same machine parameters and can therefore serve as a fingerprint for the machine state.

The micro-bunching instability has been studied at many light sources, e.g. ALS [5], Bessy II [6], DIAMOND [7]. At the KArlsruhe Research Accelerator (KARA) (the storage∗ miriam.brosi@kit.edu
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MEASUREMENT SETUP

Figure 1: Fluctuation spectrogram of the emitted THz power. The fluctuations are caused by the instability and depend on the present machine settings. The left panel shows the extracted low frequency over bunch current corresponding to the repetition rate of the out-bursts in THz emission.

For detailed studies of the instability behavior, precise measurements of the development of the emitted CSR power as a function of time as well as of the bunch currents are necessary. Therefore fast THz detectors, in this case Schottky barrier diode detectors from ACST [12] or VDI [13], are read-out with the in-house developed fast data-acquisition system KAPTURE [14]. This system samples and stores the detector pulse height (500 MHz) leaving out the noise during the 2 ns in-between pulses. With this combination of fast detectors and memory efficient read-out, the peak power of the THz pulse emitted from each bunch at every
Table 1: Machine Parameters

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Value</th>
</tr>
</thead>
<tbody>
<tr>
<td>Energy</td>
<td>1.3 GeV</td>
</tr>
<tr>
<td>RF voltage</td>
<td>771 kV</td>
</tr>
<tr>
<td>Filling pattern</td>
<td>mixed currents</td>
</tr>
<tr>
<td>Synchrotron frequency</td>
<td>7.5, 7.7, 7.95 kHz</td>
</tr>
<tr>
<td>Horizontal tune</td>
<td>0.7863 ± 0.0001</td>
</tr>
<tr>
<td>Vertical tune</td>
<td>0.7992 ± 0.0001</td>
</tr>
</tbody>
</table>

The storage ring quadrupoles are powered in five families. The individual powering is not foreseen at present, not allowing local tune compensation. Hence, the optics was optimized not just to compensate the tune shifts, but also to minimize the maximum beta beat as well as the asymmetry of the beta functions. Though we only measured the tunes while optimizing the machine, we are quite confident, that the optics is as “symmetric” as in the simulations and therefore the beta beat at the measurement point of the THz frequency (“Infrared2” in Fig. 2) is also relatively small. The optics optimization was done beforehand using elegant [18] and a LOCO [19] based model. Nevertheless, the beta functions are not completely compensated, as can be seen in Fig. 2.

With the help of the simulated optics the wiggler was ramped up step-wise to 2 T whilst the transverse tunes were measured with the bunch-by-bunch system iGp12, see e.g. [20], to an accuracy of 10⁻⁴. At each ramping step, the transverse tunes as well as the marginally changed synchrotron tune were corrected using the quadrupole families and the RF frequency if necessary. After this machine optimization we reproducibly achieved the setup summarized in Table 1.

Calculations using well-known equations [21] show that the momentum compaction factor only changes by 10⁻⁷ which is negligible compared with the original momentum compaction factor of about 3 × 10⁻⁴, therefore we did not put special efforts into compensating it at this time.

The measurements were done in separate fills (A - E). For the sake of completeness, the synchrotron frequency \( f_s \) of fill A and B differs slightly from the others. With this set of fills, we cover two cases—wiggler on and wiggler off—for the same range of bunch currents. Furthermore, fill C includes the transition from one case to the other as shown in Fig. 3.

**RESULTS**

The THz fluctuation spectrograms for the cases with wiggler on or off show an overall similar appearance.

For example, the threshold \( I_{th} \) of the instability, the current above which fluctuations in the emitted THz power occur, is the same for all fills (see Tab. 2, fill D did not reach low enough currents). That indicates, the CLICow and therefore the longitudinal damping time has no significant influence on the threshold current. This is in agreement with the argument in [2] that the micro-bunching instability is a strong instability and hence its threshold should be independent from the damping time. The resulting approximation for the threshold (which is independent from the damping time) was derived by assuming that the THz fluctuations are due to a micro-bunching instability.
Table 2: Bunch Current and Frequency at Instability Threshold

<table>
<thead>
<tr>
<th>Property</th>
<th>A</th>
<th>B</th>
<th>C</th>
<th>E</th>
</tr>
</thead>
<tbody>
<tr>
<td>$B_{wig}$/ T</td>
<td>0</td>
<td>0</td>
<td>0 → 2</td>
<td>2</td>
</tr>
<tr>
<td>$I_{th}$/ µA</td>
<td>217 ± 3</td>
<td>213 ± 3</td>
<td>215 ± 2</td>
<td>220 ± 4</td>
</tr>
<tr>
<td>$f_{th}$/ kHz</td>
<td>30.9 ± 0.3</td>
<td>30.1 ± 0.3</td>
<td>29.6 ± 0.3</td>
<td>29.7 ± 0.3</td>
</tr>
</tbody>
</table>

Figure 3: Low bursting frequency (periodicity of radiation outbursts) as a function of bunch current for different fills. Shift in frequency visible for CLICow at 0 T or 2 T.

proven to concur with measurements to a great extend in [3]. For the settings used in these fills, the simple scaling law predicts a threshold current of $I_{th} = 207$ µA for $f_{th} = 7.7$ kHz.

Also, the fluctuations directly above the instability threshold have the same frequency $f_{th}$ (Tab. 2) and don’t seem to be changed significantly by changes of the damping time.

The low frequency of the fluctuations in the emitted THz power (the periodicity of the radiation outbursts), however, shows a significant difference between the measurements with CLICow on and CLICow off. This low bursting frequency is displayed as a function of the bunch current in Fig. 3 for the different fills. For all fills the curves show similar features, like the kinks at approximately (0.65 ± 0.01) mA and (0.40 ± 0.01) mA. Nevertheless, the curves for CLICow off lie at lower frequencies whereas the ones with CLICow on are shifted to higher frequencies. For example for a current of 0.8 mA the frequency is shifted from (240 ± 5) Hz to (310 ± 5) Hz.

That these low bursting frequencies depend on the damping time is not unexpected as can be explained with a simple model of the longitudinal dynamics during the THz outbursts. The additional potential acting on the bunch is the convolution of the wake function and the bunch profile [22]. The shorter the bunch is the stronger this additional wake potential is acting on the bunch and driving the growth of substructures. These substructures lead to the emission of coherent synchrotron radiation above the vacuum chamber cut-off, which is visible as an outburst of THz radiation. Due to filamentation and diffusion the substructures are smeared out at a point in time, making the bunch longer. For a longer bunch the wake potential is significantly weaker and the bunch length is damped down until it is short enough to generate a strong wake potential leading again to the growth of substructures and another repetition of this cycle. Such a cycle is visible in the bunch length and the energy spread as a saw-tooth like pattern [23, 24].

The time span between two outbursts at a given bunch current $I_{th}$ consists of two parts. The first part, the rise time of the bunch length is caused by the occurrence and filamentation of the substructures. This time changes as a function of $I_{th}$. The second part is the time it takes to damp down the bunch length from its maximum to its minimum. On the one hand, this depends strongly on the longitudinal damping time and explains how the damping time affects the repetition rate of the outbursts. On the other hand, it depends on the minimal and maximal bunch length at $I_{th}$.

As the bunch length decreases with current also the interaction between the longitudinal charge distribution and the impedance changes. Therefore, the low bursting frequency can change as a function of bunch current even for a constant damping time as seen in Fig. 3. A faster damping results in a similar behavior, shifted to higher frequencies.

The dependency of the low bursting frequency on the longitudinal damping time was also simulated with the Vlasov-Fokker-Planck solver Inovesa [25]. Changing only the damping time while leaving all other parameters unchanged resulted in a qualitative agreement of the shift of the low frequency with that seen in the measurements.

SUMMARY AND OUTLOOK

By using a prototype CLIC damping wiggler installed at the Karlsruhe Research Accelerator (KARA), the dependency of some key properties of the micro-bunching instability on the longitudinal damping time was studied.

No significant changes of the threshold current and the high frequency directly above the threshold were observed. The low bursting frequency, equivalent to the repetition rate of the outburst in CSR, however, significantly shifted when the CLICow was ramped up from 0 T to 2 T.

This observation is supported by similar results with a Vlasov-Fokker-Planck solver.

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REFERENCES


